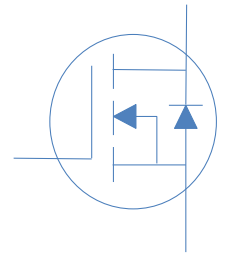


80V N-Ch Power MOSFET

V_{DS}	80	V
$R_{DS(on),typ}$	1.6	m
I_D (Silicon Limited)	294	A
I_D (Package Limited)	240	A

Part Number	Package	Marking
HGT019N08A	TOLL	GT019N08A



Absolute Maximum Ratings at $T_J=25^{\circ}\text{C}$ (unless otherwise specified)

Parameter	Symbol	Conditions	Value	Unit
Continuous Drain Current(Silicon limited)	I_D	$T_C=25^{\circ}\text{C}$	294	A
		$T_C=100^{\circ}\text{C}$	208	
Continuous Drain Current(Package limited)		$T_C=25^{\circ}\text{C}$	240	
Drain to Source Voltage	V_{DS}	-	80	V
Gate to Source Voltage	V_{GS}	-	± 20	V
Pulsed Drain Current	I_{DM}	-	900	A
Avalanche Energy, Single Pulse	E_{AS}	$L=0.1\text{mH}, T_C=25^{\circ}\text{C}$	180	mJ
Power Dissipation	P_D	$T_C=25^{\circ}\text{C}$	319	W
Operating and Storage Temperature	T_J, T_{stg}	-	-55 to 175	$^{\circ}\text{C}$

Absolute Maximum Ratings

Parameter	Symbol	Max	Unit
Thermal Resistance Junction-Ambient	R_{JA}	60	$^{\circ}\text{C}/\text{W}$
Thermal Resistance Junction-Case	R_{JC}	0.47	$^{\circ}\text{C}/\text{W}$

Electrical Characteristics at $T_J=25^{\circ}\text{C}$ (unless otherwise specified)

Static Characteristics

Parameter	Symbol	Conditions	Value			Unit
			min	typ	max	
Drain to Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS}=0V, I_D=250\text{ A}$	80	-	-	V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS}=V_{DS}, I_D=250\text{ A}$	2.0	2.7	4.0	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{GS}=0V, V_{DS}=80V, T_J=25^{\circ}\text{C}$	-	-	1	A
		$V_{GS}=0V, V_{DS}=80V, T_J=100^{\circ}\text{C}$	-	-	100	
Gate to Source Leakage Current	I_{GSS}	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	± 100	nA
Drain to Source on Resistance	$R_{DS(on)}$	$V_{GS}=10V, I_D=20A$	-	1.6	1.9	m
Transconductance	g_{fs}	$V_{DS}=5V, I_D=20A$	-	79	-	S
Gate Resistance	R_G	$V_{GS}=0V, V_{DS}\text{ Open}, f=1\text{MHz}$	-	0.59	-	

Dynamic Characteristics

Input Capacitance	C_{iss}		-	8628	-	
Output Capacitance	C_{oss}	$V_{GS}=0V, V_{DS}=40V, f=1\text{MHz}$	-	1396	-	pF
Reverse Transfer Capacitance	C_{rss}		-	34	-	
Total Gate Charge	$Q_g(10V)$		-	135	-	
Gate to Source Charge	Q_{gs}	$V_{DD}=40V, I_D=20A, V_{GS}=10V$	-	28	-	nC
Gate to Drain (Miller) Charge	Q_{gd}		-	36	-	
Turn on Delay Time	$t_{d(on)}$		-	30	-	
Rise time	t_r	$V_{DD}=40V, I_D=20A, V_{GS}=10V,$	-	-	-	ns
Turn off Delay Time	$t_{d(off)}$	$R_G=10\ \Omega$	-	70	-	
Fall Time	t_f		-	32	-	

Reverse Diode Characteristics

Diode Forward Voltage	V_{SD}	$V_{GS}=0V, I_F=20A$	-	-	1.2	V
Reverse Recovery Time	t_{rr}	$V_R=40V, I_F=20A, dI_F/dt=100A/\text{s}$	-	72	-	ns
Reverse Recovery Charge	Q_{rr}		-	108	-	nC

Fig 1. Typical Output Characteristics

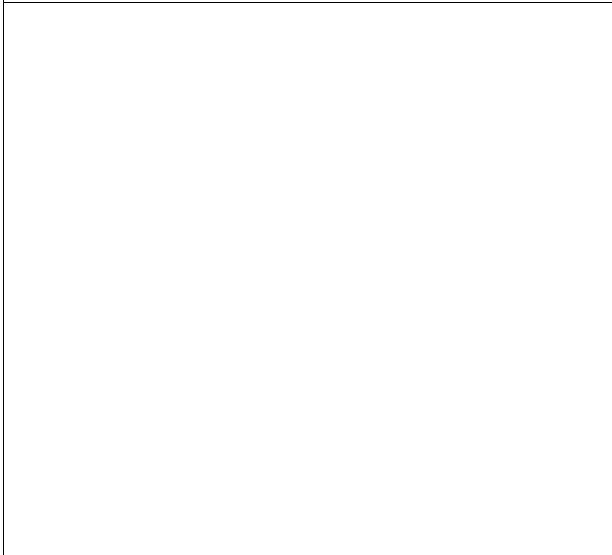


Figure 2. On-Resistance vs. Gate-Source Voltage

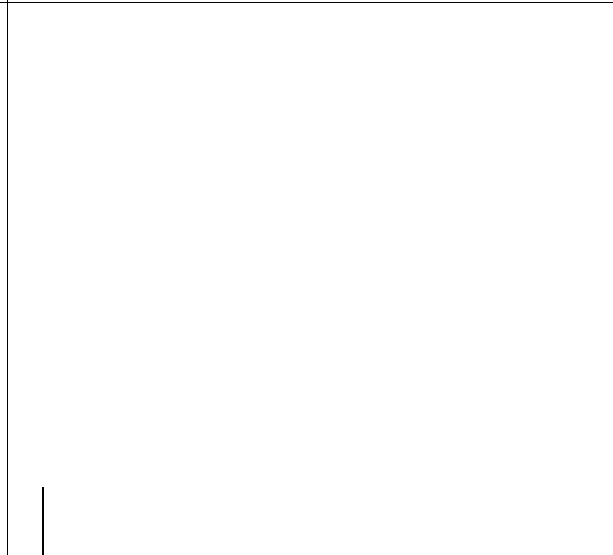


Figure 3. On-Resistance vs. Drain Current and Gate Voltage

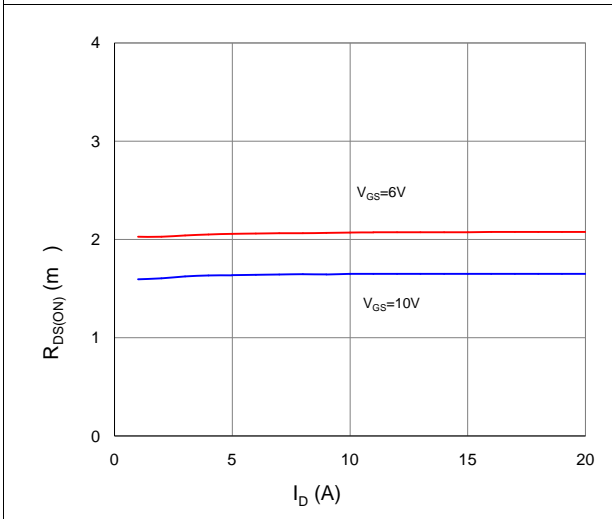


Figure 4. Normalized On-Resistance vs. Junction Temperature

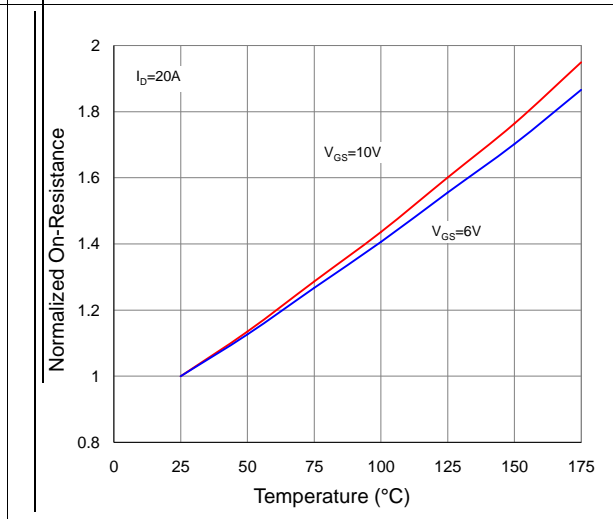


Figure 5. Typical Transfer Characteristics

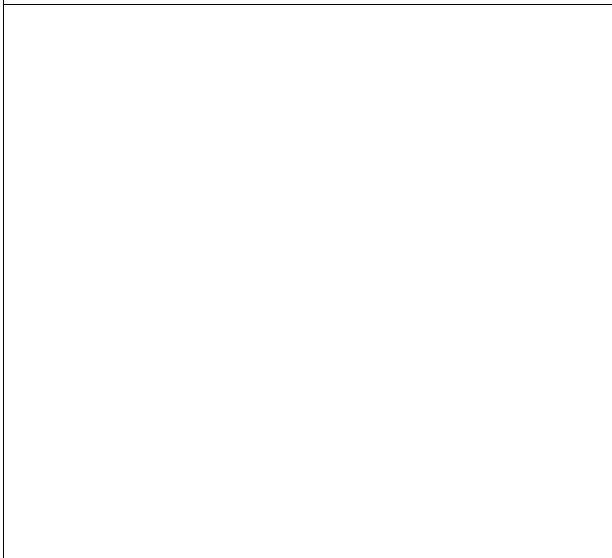


Figure 6. Typical Source-Drain Diode Forward Voltage

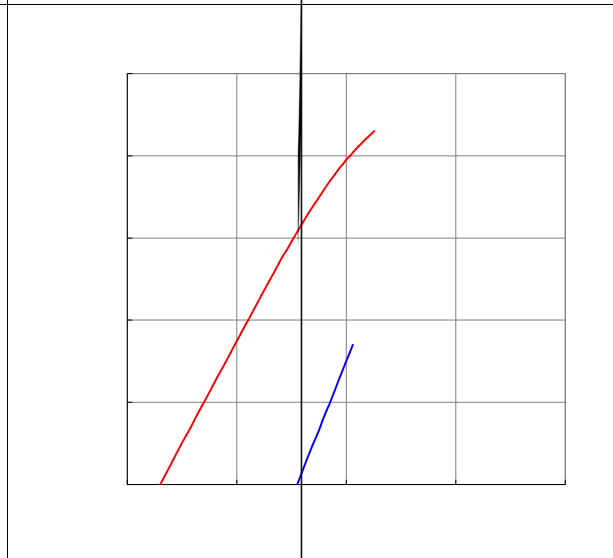


Figure 7. Typical Gate-Charge vs. Gate-to-Source Voltage

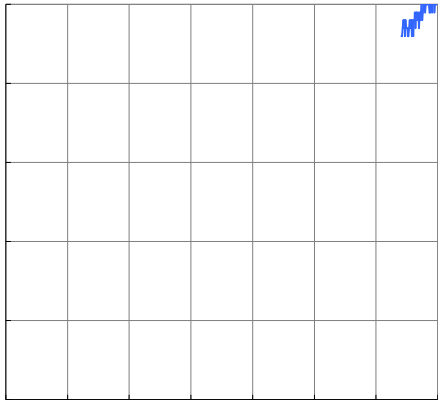


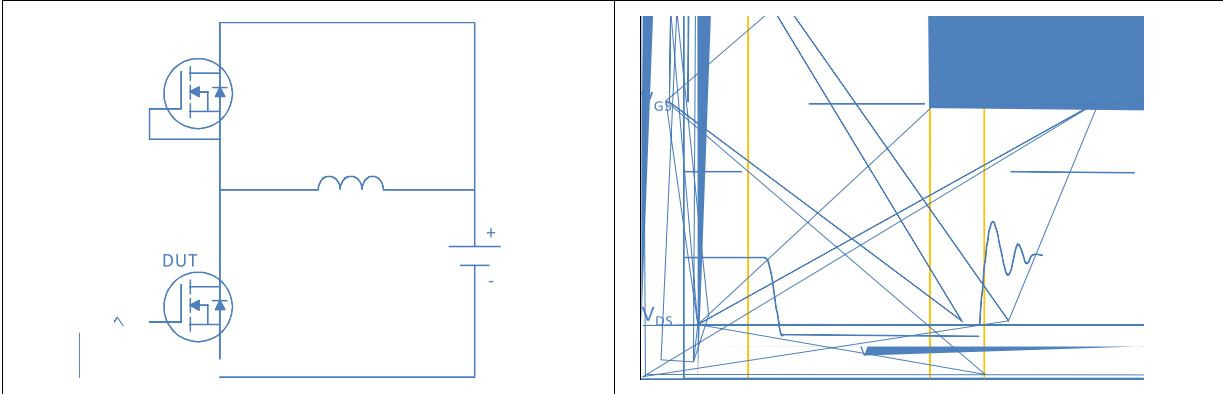
Figure 8. Typical Capacitance vs. Drain-to-Source Voltage

Figure 9. Maximum Safe Operating Area

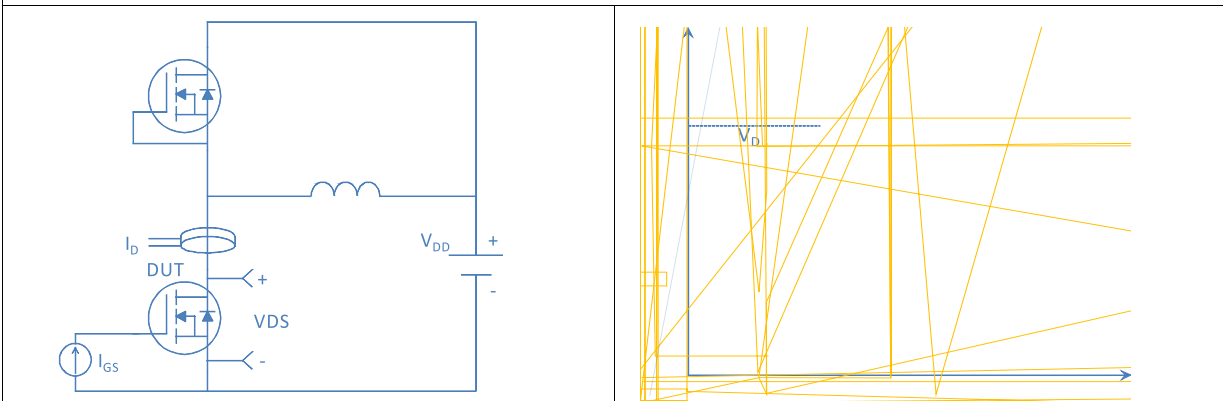
Figure 10. Maximum Drain Current vs. Case Temperature

Figure 11. Normalized Maximum Transient Thermal Impedance, Junction-to-Ambient

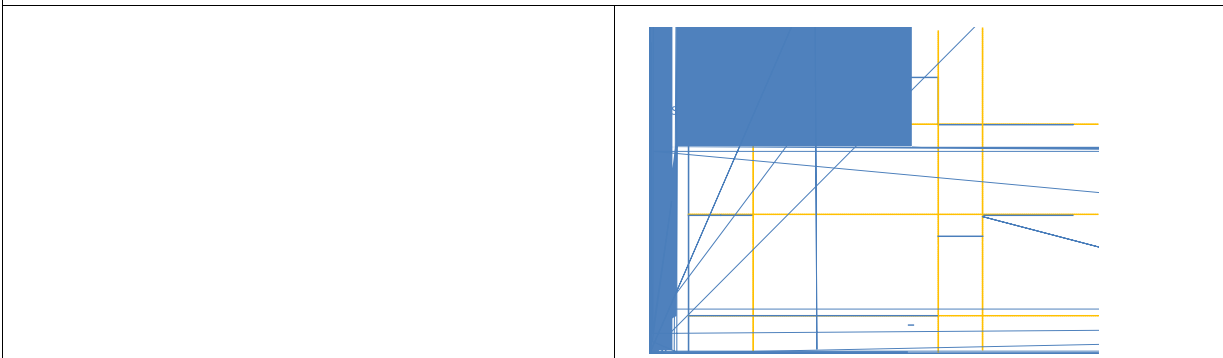
Inductive switching Test



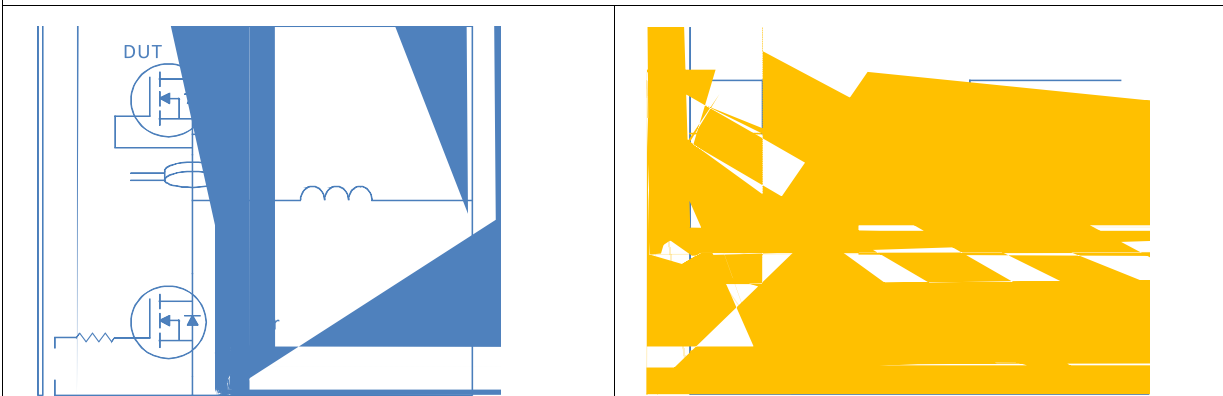
Gate Charge Test



Uclamped Inductive Switching (UIS) Test

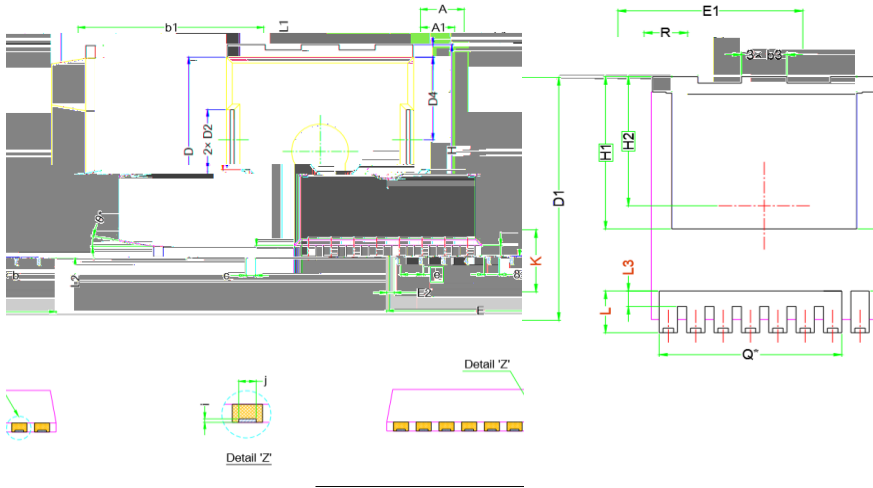


Diode Recovery Test



Package Outline

TOLL, 8 leads



SYMBOL	DIMENSIONS		
	MIN.	NOM.	MAX.
A	2.20	2.30	2.40
A1	1.70	1.80	1.90
b	0.70	0.80	0.90
b1	9.70	9.80	9.90
b3	1.90	2.00	2.10
c	0.40	0.50	0.60
D	10.28	10.38	10.48
D1	10.98	11.08	11.18
D2	3.20	3.30	3.40
D4	4.45	4.55	4.65
E	9.80	9.90	10.00
E1	8.00	8.10	8.20
E2	0.30	0.40	0.50
e	1.20 BSC		
H	11.58	11.68	11.78
H1	6.95 BSC		
H2	5.89 BSC		
i	0.10 REF.		
j	0.46 REF.		
K	2.80 REF.		
L	1.60	1.90	2.10
L1	0.60	0.70	0.80
L2	0.50	0.60	0.70
L3	0.60	0.70	0.80
N	8		
R	2.00	1.80	1.90
Q	10° REF.		